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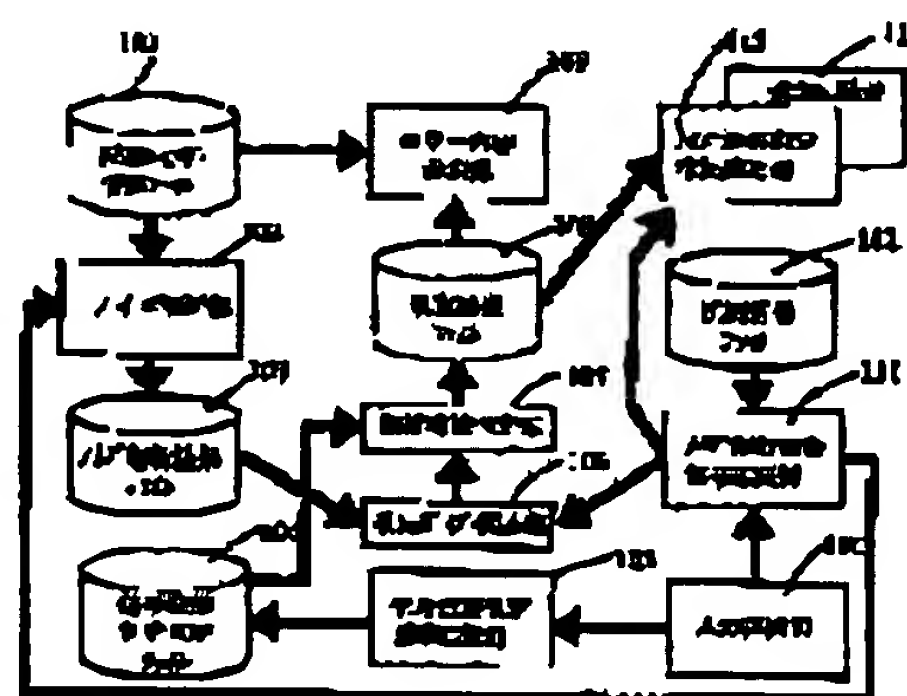
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(54) METHOD AND DEVICE FOR JUDGING NOISE ANALYTIC RESULT OF TRANSMISSION LINE

(57)Abstract:

PROBLEM TO BE SOLVED: To facilitate the judging operation of the signal waveform of a noise analytic result in the noise analytic operation of a signal waveform flowing through the transmission line of a printed board.

SOLUTION: An input device part 110 inputs a criterion to a signal waveform criterion storing part 105 and a noise analyzing object signal to a noise analyzing object signal editing part 111. Then, the editing part 111 fetches connection information from a connection information file 112 and sends connection information of analyzing object signal, a using part type, etc., to a judging point searching part 106 and a noise analytic part 102. The



analytic part 102 analyzes noise from wiring layout information and analyzing object signal information. An analytic result judging part 107 judges the signal waveform of a judging point searched from the signal waveform of the noise analytic result by the searching part 106 by a signal waveform judging criterion. The judging result is stored in a file 108, error contents are displayed on an error contents display part 109 and the judging result is outputted to a noise analytic judging result gathering table 113.

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